## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | VERWEG ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,440,452	08-1995	Kitahara, Akira	361/773
*	В	US-2005/0142917 A1 .	06-2005	Verweg et al.	439/212
*	C	US-2005/0237424 A1 .	10-2005	Weekamp et al.	348/373
*	D	US-6,486,412 B2	11-2002	Kato, Hiroki	174/260
*	Е	US-7,078,788 B2	07-2006	Vu et al.	257/668
*	F	US-7,067,356 B2	06-2006	Towle et al.	438/122
*	G	US-7,053,381 B2	05-2006	Shaw et al.	250/370.11
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P					
	Q					
	R					
	s					
54	Т					

## **NON-PATENT DOCUMENTS**

*	,	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.